

TUG 2010 Monday

Updated: 5/3/2010

Sunday - May 2, 2010

4:00 - 6:00 p.m.	Conference Check-In - West Registration Counter
4:00 - 6:00 p.m.	Welcome Reception - Basshead Deck

Monday - May 3, 2010

Teradyne Users Group 2010

7:30 - 8:30	Breakfast	Breakfast	Breakfast	Breakfast	Breakfast	Breakfast
8:30 - 9:00	Welcome	Welcome	Welcome	Welcome	Welcome	Welcome
9:00 - 10:00	Keynote Address	Keynote Address	Keynote Address	Keynote Address	Keynote Address	Keynote Address
10:00 - 10:30	Break	Break	Break	Break	Break	Break
GROUP	TEST INFRASTRUCTURE AND PRODUCTION	MIXED SIGNAL	RF WIRELESS	DIGITAL	POWER AUTOMOTIVE	ASSEMBLY TEST DEFENSE & AEROSPACE
10:30 - 12:00	Front Nine			Now the Testing Starts	Test Techniques	Analog
10:30 - 11:00	16 Block-Based Test Methodology on the Nextest Magnum Using Excel	43 How to Test ADCs with Sample Rates Greater than 100 MSPS on the FLEX	3 UltraWave Receiver Modes (What is "Normal," Anyway?)	7 Memory Controller Test Using Protocol Aware Test Methodologies	116 Regulator Testing...No Supplies, No Problem!	113 Averaging in the Ai-760 DSO
11:00 - 11:30	119 Using Dynloader for Debugging	27 How to Extend the Voltage Range of HSD200	71 How to Improve Intermodulation Test Practices	79 GUI Pin Margin Tool	12 How to Trim Temperature Coefficients with DLT	135 Simulating Basic Semiconductor Testing and Curve Tracing Using the Ai-760 or Ai-710
11:30 - 12:00	89 Script Engine for Nextest Family of Testers	52 Low-Voltage Measurements: How Low is Low?	4 Test Time Reduction Method for Testing I/Q Driven Tx 1dB Compression Tests	60 Compensating for DC Voltage Drop in Production		136 Prioritizing Ai-710 Rehost Candidates Through ATLAS Source Code Analysis
12:00 - 1:00	Lunch	Lunch	Lunch	Lunch	Lunch	Lunch
1:00 - 2:30	Irons			Large Site Count Tests	Test Techniques- Eagle	Digital
1:00 - 1:30	112 Set up an Apache SVN Server to Bring Revision Control and Test Program Management to Your Organization	46 WORKSHOP 1-2:30: Understanding Multisite Variables	58 WORKSHOP 1-2: How to Use the ESA Toolkit for Modulation and Demodulation Testing	2 Modeling Test Economics for High Site Count Parallel Test	1 Benefits of Floating Resources	54 Using the Bi4-Series to Test a Custom Manchester-Encoded Serial Data Bus
1:30 - 2:00	13 Test Documentation Generation in HTML Out of Comments in the Program Code and a Datalog			41 High Channel Count External Instrument Integration with J750	93 How to Measure Fast Rise/Fall Times on an Eagle Tester: Comparator to Convert to Prop Delay	137 Di as a Serial Interface
2:00 - 2:30	95 Advanced Platform Concept for Team Collaboration			44 WiMAX RF Testing with the ESA	83 HPT on the J750 for More Than 32 Sites: Best Practices	66 Digital Threshold Testing
2:30 - 3:00	Break	Break	Break	Break	Break	Break
3:00 - 5:00	On the Green			High-Speed Protocol	Test Quality	Digital Runtime Workshop

TUG 2010 Tuesday

GROUP	TEST INFRASTRUCTURE AND PRODUCTION	MIXED SIGNAL	RF WIRELESS	DIGITAL	POWER AUTOMOTIVE	ASSEMBLY TEST DEFENSE & AEROSPACE
1:00 - 2:30	On the Green			IG-XL Utilities		TPS Rehost
1:00 - 1:30	124 User Tools in the Nextest Software Environment	Attend either workshop.	147 WORKSHOP 1-2:30: What's New in Teradyne Test Cell and Device Interface Solutions	150 WORKSHOP 1-2:30: ASCII Utils & IG-XL Utils seminars (45 mins each)	Attend either workshop.	105 Transferring Legacy B2 DIFA Programs to the VDATS Using ConverterStudio: An Analysis
1:30 - 2:00	88 Log File Utilities for Nextest Magnum Family of Testers			1-1:45: ASCII Utils Seminar		
2:00 - 2:30	123 Debugging Templated Data Structures			1:45-2:30: IG-XL Seminar (for FLEX and UltraFLEX)		
2:30 - 3:00	Break	Break	Break	Break	Break	59 Non-ATLAS Module Prototyping with Xpress Services
3:00 - 4:30	ENGINEERING UPDATES					
3:00-3:30	Semiconductor Programs Business Meetings					ATD Defense & Aerospace Business Meeting
3:30 - 4:30	7a Semiconductor Engineering updates					ATD Defense & Aerospace Engineering Updates
4:30 - 6:30	ROUNDTABLES/POSTER SESSIONS					
	90 User Variable Show/Hide Utilities for Nextest Family of Testers	35 FlexIm Licensing Basics	144 Meet the Designers	69 Utilizing J750 VP12 1A Limited Utility Power and How to Prevent Corrupted HRAM	130 IGBT Test by Eagle ETS-88	47 The SMART Tool
	146 DIBViewer	45 Sampling a Signal from a Digital Pattern	145 Keep the End in Mind	17 HSD1000/UltraPin800 DriverMode Tutorial – What Is It, Why Should We Care About It, and How to Set It In Your Test Program	11 How to Create a DIB Check Program with Excel and VBA	143 Top 10 DIB Errors to Avoid
	42 How to Increase the J750 Parallel Site Count with the X750 Device Power Supply	126 Dynamic Characteristic Measurement of ADC in J750	153 Help our Help	9 HALI (HSD Auto Loop Inserter) 2.0		

TUG 2010 Wednesday

Updated: 5/12/2010

Wednesday - May 5, 2010

Teradyne Users Group 2010

7:30 - 8:30	Breakfast	Breakfast	Breakfast	Breakfast	Breakfast
GROUP	TEST INFRASTRUCTURE AND PRODUCTION	MIXED SIGNAL	RF WIRELESS	DIGITAL	POWER AUTOMOTIVE
8:30 - 10:00	Golf School			Understanding Pattern Failures	PMA Accelerating Test Development
8:30 - 9:00	8 Introduction to IG-IatoR	78 Mixed Signal Concurrent Test	74 Seminar 8:30-10: Introduction to RF ATE Testing for Non-RF Test Engineers		32 IG-XL DSP: Advanced Features and IG-XL Internals
9:00 - 9:30	106 Adaptive Test at its Best with Teradyne's FLEX and OptimalTest	77 How to Implement Concurrent Pattern Burst on the FLEX		29 Scan Failure Diagnostics for UltraFLEX	102 An IG-XL Sheet-Based Interface for Serial Communication Testing on the FLEX
9:30 - 10:00	30 How to Add TDR Verification in Production When Digital Channels are Incorrectly Masked			98 Script-Enabled Reusable HRAM	
10:00 - 10:30	Break	Break	Break	Break	Break
10:30 - 12:00	On Course Corrections			When Digital Approaches RF	PMA Test Time Optimization
10:30 - 11:00	151 WORKSHOP 10:30-12: Trials and Tribulations of Using Revision Control with IG-XL	80 How to Test Multi-Blocks in Parallel with the FLEX	74 Seminar 10:30-12: Introduction to RF ATE Testing for Non-RF Test Engineers (cont.)	86 Jitter Injection Module for Testing 10G SerDes	67 Test Optimization Techniques for Mobile Device PMICs
11:00 - 11:30		48 Charting a Course for Concurrent Test Success		18 How to Use PPMU to Simulate a Virtual Resistor for LVDS VoD/VoCM Measurement	34 PSETs Revisited: A Compilation of Unusual Applications from Hard Disk Drive Power Devices
11:30 - 12:00		70 Tips for UltraFLEX to FLEX Conversion		108 Programming UltraWave 12G with a Digital Pattern	22 Charting IG-XL's Test Time Measurement Capabilities
12:00 - 1:00	Lunch	Lunch	Lunch	Lunch	Lunch

TUG 2010 Wednesday

GROUP	TEST INFRASTRUCTURE AND PRODUCTION	MIXED SIGNAL	RF WIRELESS	DIGITAL	POWER AUTOMOTIVE
1:00 - 2:30	19th Hole			Stretching the Testers	
1:00 - 1:30	125 DBM Methodologies, Best Practices, and Lessons Learned from FPGA Testing on Magnum	142 WORKSHOP 1-2:30: Data Analysis Workshop	85 Alternative De-embedding Solution for S-Parameters Test on Gen4	55 Using the VBT Overlay Language to Change Levels and Timings	
1:30 - 2:00	10 Automated Test Program Development Using Python		92 MEMS High Speed Switch Module	56 Using Keepalive to Simplify Programming of Registers Setup on the UltraFLEX	
2:00 - 2:30	131 One Approach to Leveling a PCB with IP750				